FISCHERSCOPE® X-RAY XAN® 220 FISCHERSCOPE® X-RAY XAN® 222

X-Ray Fluorescence Measuring Instruments for fast and non-destructive Analysis and Coating Thickness Measurement of Gold and Silver Alloys





Description

The FISCHERSCOPE X-RAY XAN 220 and XAN 222 are optimized X-ray fluorescence measuring instruments for non-destructive analysis of jewelry, coins and precious metals.

They are particularly suited for the analysis of precious metals and their alloys in composition and coating thickness. Up to 24 elements in the range of Chlorine (17) to Uranium (92) can be determined simultaneously.

Typical fields of application are the analysis of:

- Jewelry, precious metals and dental alloys
- Yellow and white gold
- Platinum and silver
- Rhodium
- Alloys and coatings
- Multi layer coatings

Outstanding accuracy and long-term stability are characteristics of all FISCHERSCOPE X-RAY systems. The necessity of recalibration is dramatically reduced, saving time and effort.

The modern silicon drift detector achieves high accuracy and good detection sensitivity.

The fundamental parameter method by FISCHER allows for the analysis of solid and liquid specimens as well as coating systems without calibration.

Design

The XAN 220 and XAN 222 are designed as user-friendly bench-top instruments. They differ in the support stage and the housing size:

- XAN 220: Fixed sample support
- XAN 222: Manually operable XY stage for accurate positioning of small parts and larger measuring chamber

For quick and easy sample positioning, the X-ray source and semiconductor detector assembly is located in the instrument's lower chamber. The measuring direction is from underneath the sample, which is supported by a transparent window.

The integrated video-microscope with zoom and crosshairs simplifies sample placement and allows precise measuring spot adjustment.

The entire operation and evaluation of measurements as well as the clear presentation of measurement data is performed on a PC, using the powerful and user-friendly $WinFTM^{\textcircled{\tiny B}}$ software.

The FISCHERSCOPE X-RAY XAN 220 and XAN 222 fulfill DIN ISO 3497 and ASTM B 568. The XAN 220 is a fully protected instrument with type approval according to the German regulations "Deutsche Röntgenverordnung-RöV".

General Specification

Intended use Energy dispersive X-ray measuring instrument (EDXRF) to analyze precious metals and

their alloys in composition and coating thickness.

Element range Chlorine (17) to Uranium (92) – up to 24 elements simultaneously

Repeatability $\leq 0.5 \%$ for gold, measurement time 60 sec Design Bench top unit with upwards opening hood

Measuring direction Bottom up

X-Ray Source

X-ray tube Micro-focus tungsten tube with beryllium window

High voltage Three steps: 30 kV, 40 kV, 50 kV

Aperture (Collimator) Ø 1 mm (39 mils), optional Ø 2 mm (79 mils) or Ø 0.6 mm (23.6 mils)

Measurement spot Aperture diameter plus 200 µm (8 mils), at measurement distance MD = 0 mm

X-Ray Detection

X-ray detector Silicon Drift Detector (SDD), peltier-cooled

Resolution (fwhm for Mn- K_{α}) $\leq 160 \text{ eV}$

Measuring distance 0 ... 25 mm (0 ... 1 in)

Distance compensation with patented DCM method for simplified measurements at varying distances. For particular applications or for higher demands on accuracy an

additional calibration might be necessary.

Sample Alignment

Sample positioning Manually

Video microscope High-resolution CCD color camera for optical monitoring of the measurement location

along the primary beam axis,

Crosshairs with a calibrated scale (ruler) and spot-indicator,

Adjustable LED illumination

Zoom factor Digital 1x, 2x, 3x, 4x

Sample StageXAN 220XAN 222DesignFixed sample supportManually operable XY stageUsable sample placement area310 x 320 mm (12.2 x 12.6 in)Max. sample weight13 kg (29 lb)2 kg (4.4 lb)

 Max. sample weight
 13 kg (29 lb)
 2 kg (4.4 lb)

 Max. sample height
 90 mm (3.5 in)
 174 mm (6.8 in)

Electrical data

Power supply AC 115 V or AC 230 V 50 / 60 Hz

Power consumption max. 120 W, without evaluation PC

Protection class IP40

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Dimensions	XAN 220	XAN 222	
External dimensions	403 x 588 x 365 mm	403 x 588 x 444 mm	
Width x depth x height	$(16 \times 23.2 \times 14.4 \text{ in})$	$(16 \times 23.2 \times 17.5 \text{ in})$	
Weight	Approx. 45 kg (99 lb)		
Environmental Conditions			
Operating temperature	10 °C − 40 °C / 50 °F − 104 °F		
Storage/Transport temperature	0 °C – 50 °C / 32 °F – 122 °F		
Admissible air humidity	≤ 95 %, non-condensing		
Evaluation unit			
Computer	Windows [®] -PC		
Software	Standard: Fischer WinFTM [®] BASIC including PDM [®] , Optional: Fischer WinFTM [®] SUPER		
Standards	XAN 220	XAN 222	
CE approval	EN 61010		
X-Ray standards	DIN ISO 3497 and ASTM B 568		
Approval	Fully protected instrument with type approval according to the German regulations "Deutsche Röntgenverordnung-RöV".	Individual acceptance inspection as a fully protected instrument according to the German regulations "Deutsche Röntgenverordnung-RöV".	
Order			
FISCHERSCOPE X-RAY XAN 220	604-771		
FISCHERSCOPE X-RAY XAN 222	604-772		

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